

4/16/2014



RELIABILITY MONITOR REPORT  
FOR

**MFN Complementary BiCMOS (CB50)**

**MAXIM INTEGRATED**

160 RIO ROBLES  
SAN JOSE, CA 95134

This Report was prepared by  
**MAXIM INTEGRATED Reliability Engineering**

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX3728ACTE	MAX3738ETG+	MAX3747AEUB	MAX3747CETG
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The calculated failure rate for devices using this process is:

**FAILURE RATE: MTTF (YRS): 60045 QUANTITY: 592 FAILS: 0 FITS: 1.9**

The parameters used to calculate this failure rate are as follows:

**Cf: 60% Ea: 0.7 Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2013 and 3/31/2014 .

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**Process Information:**

Process Description: MFN Complementary BiCMOS (CB50)

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**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1309	MAX3747CETG+	135°C	1000 HRS	78	0	JHDYC3058C
HIGH TEMP OP LIFE	1311	MAX3738ETG+	135°C	500 HRS	80	0	JJR1A2119AA
HIGH TEMP OP LIFE	1332	MAX3738ETG+	135°C	192 HRS	80	0	JAMI63135AA
HIGH TEMP OP LIFE	1332	MAX3738ETG+	135°C	500 HRS	80	0	JAMI63155AA
HIGH TEMP OP LIFE	1333	MAX3738ETG+	135°C	500 HRS	80	0	JAMI63156BA
HIGH TEMP OP LIFE	1338	MAX3738ETG+	135°C	500 HRS	80	0	JJR1A2119BA
HIGH TEMP OP LIFE	1339	MAX3728ACTE+	135°C	500 HRS	34	0	JA0Y6Z039YA
HIGH TEMP OP LIFE	1341	MAX3747AEUB+	135°C	500 HRS	80	0	JHDZE2111Z
					<b>Total:</b>	<b>0</b>	
<b>FAILURE RATE:</b>	<b>MTTF (YRS): 60045</b>	<b>QUANTITY: 592</b>	<b>FAILS: 0</b>	<b>FITS: 1.9</b>			